

SFT9500

COATING THICKNESS GAUGE



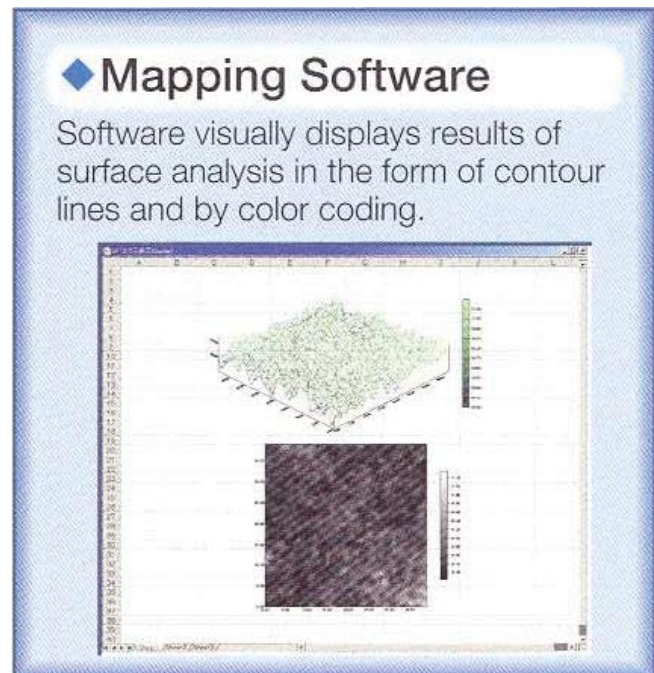
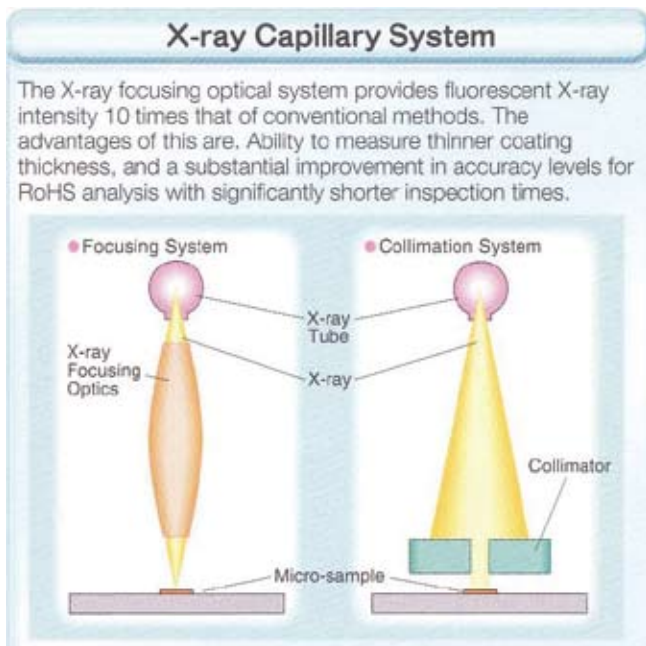
SFT9500 ist ein Hochleistungs-RFA-Schichtdickenanalysator. Die 75 Watt Röntgenröhre erzeugt zusammen mit der verwendeten Röntgenoptik einen intensiven, scharf gebündelten Röntgenstrahl von weniger als 0,1 mm Durchmesser. Die erzeugte hohe Intensität erlaubt ebenfalls die Analyse von Proben auf die, gemäss der RoHS Direktive verbotenen Elemente Pb, Cd, Cr, Hg und Br. Der integrierte, hochauflösende Si-Detektor ist elektrisch gekühlt und benötigt daher keinen flüssigen Stickstoff. Seine extreme Zählratenstabilität ermöglicht kurze Messzeiten bei hoher Genauigkeit.

SFT9500 is a high performance XRF Coating Thickness Gauge with RoHS Capability. The 75 w Xray tube combined with a xray focusing system (capillary) creates a high intensity xray beam with a beam size less than 0,1 mm diameter. This allows the SFT9500 to measure micro-spot and thin film application like lead frames, connectors and flexible PCBs. The built-in high resolution Si-detector is electrically cooled and therefore needs no liquid nitrogen. Its extreme high count rate stability reduces measurement time at a high precision level. These features are excellent for measuring hazardous substances (RoHS) as well as coating thickness of thin films.



Technische Daten / Technical data:

SFT9500 Hardware		SFT9500 Software	
Elements measured	Al - U	Thin film FP (max 5 layers, 10 elements)	X
Sample type	Solid, liquid, coatings	Thin film calibration	X
Xray source	Small air-cooled tube (W)	Spectrum comparison	X
Voltage / current	50kV / 1,5 mA	KLM markers	X
Detector	Si semiconductor detector, electrically cooled	Bulk FP	X
Detector size (area)	50 mm ²	Bulk Calibration (liquids)	X
Collimator sizes	0,1 mm mono capillary	MS-Excel	X
Filter	Primary filters + 1 open position	MS-Word	X
Sample chamber (WxDxH)	600 x 320 x 170 mm	mapping	Option
Stage travel (XxYxZ)	220 x 150 x 150 mm (optional)	Spectrum matching	Option
Required space (WxDxH)	1600 x 810 x 900 mm	Image processing	Option
Weight	125 kg	HS precision judgement	Option
Sample collision prevention mechanism	X		



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*Technische Änderungen vorbehalten
 Specifications subject to change without notice.*

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